

Proton-Induced SEE

Test Org.*	Device	Function	Technology	Mfr.	Proton Energy (MeV)	Device Xsection (cm ²)	Bits Tested	Bit Xsection (cm ²)	Test Date	LU _h (MeV)	LU Xsection (cm ² /bit)	Fac.	Remarks
FIFOs													
Note: Entries in RED indicate data added since the 1997 Compendium.													
GSFC	M67204EV-50	4K x 9	SCMOS/epi RT	MHS	63			5.57E-14	1996			UCD	LaBel, et al, 97IEEE Wrkshp Rec., pg 14. Bit errors.
GSFC	M67204EV-50	4K x 9	SCMOS/epi RT	MHS	196			8.58E-14	1996			ICUF	LaBel, et al, 97IEEE Wrkshp Rec., pg 14. Bit errors.
GSFC	M67204EV-50	4K x 9	SCMOS/epi RT	MHS	196			8.30E-13	1996			ICUF	LaBel, et al, 97IEEE Wrkshp Rec., pg 14. Pointer errors.
GSFC	M67204EV-50	4K x 9	SCMOS/epi RT	MHS	196			2.00E-12	1996			ICUF	LaBel, et al, 97IEEE Wrkshp Rec., pg 14. Control errors.
GSFC	M67204EV-50	4K x 9	SCMOS/epi RT	MHS	37.1				1996	64.7		BNL	LaBel, et al, 97IEEE Wrkshp Rec., pg 14.
Legend													
Manufacturers: MHS - Matra Harris Semiconductor;													
Test Organizations													
GSFC - Goddard Space Flight Center, Greenbelt, MD													
Radiation Test Facilities													
BNL - Tandem Van de Graaff, Brookhaven National Laboratories, Long Island, NY													
IUCF - Indiana University Cyclotron Facility, Bloomington, IN													
UCD - University of California at Davis, Crocker Nuclear Laboratory, Davis, CA													